Application/Control No. Applicant(s)/Patent Under Reexamination 10/802,684 STEG, HENNING Notice of References Cited Art Unit Examiner Page 1 of 1 1732 EDMUND H. LEE **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 428/335 US-4,774,134 09-1988 Kehe et al. Α * 264/153 US-5,037,595 08-1991 Kornelis, Wiebren D. H. В US-С US-D US-Е US-F US-G US-Н US-US-US-Κ US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Name Classification Country Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** * Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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